DUAL 4-INPUT POSITIVE-NAND GATES WITH OPEN-COLLECTOR OUTPUTS DECEMBER 1983 - REVISED MARCH 1988

 Package Options Include Plastic "Small Outline" Packages, Ceramic Chip Carriers and Flat Packages, and Plastic and Ceramic DIPs

Dependable Texas Instruments Quality and Reliability

description

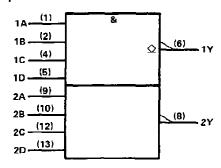
These devices contain two independent 4-input NAND gates. The open-collector outputs require pull-up resistors to perform correctly. They may be connected to other open-collector outputs to implement active-low wired-OR or active-high wired-AND functions. Open-collector devices are often used to generate higher VOH levels.

The SN5422, SN54LS22 and SN54S22 are characterized for operation over the full military temperature range of $-55\,^{\circ}\text{C}$ to $125\,^{\circ}\text{C}$. The SN7422, SN74LS22, and SN74S22 are characterized for operation from $0\,^{\circ}\text{C}$ to $70\,^{\circ}\text{C}$.

FUNCTION TABLE (each gate)

	INP	uts	OUTPUT			
A	В	С	D	Y		
Н	Н	Н	н	L		
L	X	X	x	H		
Х	L	х	х	Н		
х	×	L	×	н		
х	х	х	L	н		

logic symbol[†]



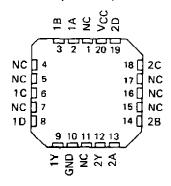
[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

Pin numbers shown are for D, J, N, and W packages.

SN5422, SN54LS22, SN54S22 . . . J OR W PACKAGE SN7422 . . . N PACKAGE SN74LS22, SN74S22 . . . D OR N PACKAGE (TOP VIEW)

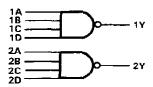
1A [] 1	U14□ Vcc
1B [2	13 🗀 2 D
NC (3	12 2 C
1C [] 4	11□ NC
1D [5	10 2B
1Y [6	9 🗀 2A
GND [7	8 🗍 2Y

\$N54L\$22, \$N54\$22 . . . FK PACKAGE (TOP VIEW)



NC-No internal connection

logic diagram



positive logic

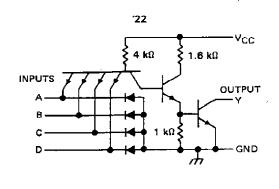
$$Y = \overline{A \cdot B \cdot C \cdot D}$$
 or $Y = \overline{A} + \overline{B} + \overline{C} + \overline{D}$

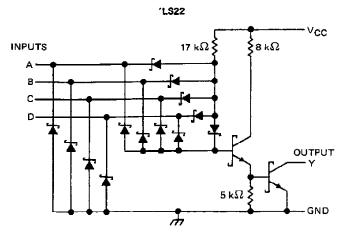
PAODUCTION DATA documents contain information current as of publication data. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.

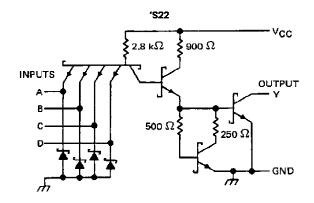


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schematics (each gate)







Resistor values shown are nominal.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, VCC (See Note 1)		
Input voltage: '22, '\$22		5.5 V
====		
Operating free-air temperature range:	SN54'	-55°C to 125°C
	SN74'	0° C to 70°C
Storage temperature range		-65°C to 150°C

NOTE 1: Voltage values are with respect to network ground terminal.



SN5422, SN7422 DUAL 4-INPUT POSITIVE-NAND GATES WITH OPEN-COLLECTOR OUTPUTS

recommended operating conditions

•			SN5422			SN7422			
		MIN	NOM	MAX	MIN	МОМ	MAX	UNIT	
Vcc	Supply voltage	4.5	5	5.5	4.75	5	5.25	٧	
VIH	High-level input voltage	2			2			V	
VIL	Low-level input voltage			8.0			0.8	٧	
Voн	High-level output voltage			5,5			5.5	٧	
loL	Low-level output current			16			16	mA	
Тд	Operating free-air temperature	- 55		125	0		70	°C	

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

242445752	TEST CONDITIONS [†]	SN5422	SN7422	TINU
PARAMETER	LEST COMPLITORS.	MIN TYP# MAX	MIN TYP [‡] MAX	UNIT
V _{IK}	$V_{CC} = MIN$, $I_{I} = -12 \text{ mA}$	-1.5	- 1.5	٧
<u></u>	VCC = MIN, VIL = 0.8 V, VOH = 5.5 V		0.25	mA
Іон	$V_{CC} = MIN$, $V_{IL} = 0.7 \text{ V}$, $V_{OH} = 5.5 \text{ V}$	0.25		INA
V _{OL}	V _{CC} = MIN, V _{IH} = 2 V, I _{OL} = 16 mA	0.2 0.4	0.2 0.4	٧
l _I	$V_{CC} = MAX$, $V_{\parallel} = 5.5 \text{ V}$	1	1	mA
ļН	V _{CC} = MAX, V _I = 2.4 V	40	40	μА
IβL	$V_{CC} = MAX$, $V_I = 0.4 V$	-1.6	-1.6	mΑ
Іссн	$V_{CC} = MAX, V_I = 0$	2 4	2 4	mA
^I CCL	$V_{CC} = MAX$, $V_I = 4.5 V$	6 11	6 11	mA

[†]For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions. [‡]All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25 \text{ °C}$.

switching characteristics, V_{CC} = 5 V, T_A = 25°C (see note 2)

PARAMETER	FROM ((NPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN TYP	MAX	UNIT
^t PLH	Any	v	$R_{\perp} = 4 k \Omega$, $C_{\perp} = 15 pF$	35	45	កទ
^t PHL	City	·	$R_L = 400 \Omega,$ $C_L = 15 pF$	8	15	ns

NOTE 2: Load circuits and voltage waveforms are shown in Section 1.



SN54LS22, SN74LS22 DUAL 4-INPUT POSITIVE-NAND GATES WITH OPEN-COLLECTOR OUTPUTS

recommended operating conditions

		SN54LS22			SN74LS22			UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	ONII
V _{CC} Sup	ply voltage	4.5	5	5.5	4.75	5	5.25	٧
V _{1H} High	n-level input voltage	2			2			٧
V _{IL} Low	elevel input voltage		•	0.7			0.8	V
V _{OH} High	n-level output voltage			5. 5			5.5	٧
IOL Low	elevel output current			4			8	mΑ
T _A Ope	rating free-air temperature	- 55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

		TEST CONDITIONS †		1	SN54LS22			SN74 LS	22	UNIT
PARAMETER				MIN	TYP\$	MAX	MIN	TYP‡	MAX	UNII
VIK	V _{CC} = MIN,	I _I = — 18 mA				- 1.5			- 1.5	٧
10Н	V _{CC} = MIN,	VIL = MAX,	V _{OH} = 5.5 V			0.1			0.1	mА
V	V _{CC} = MIN,	V _{IH} = 2 V,	IOL = 4 mA		0.25	0.4		0.25	0.4 V	
VOL	V _{CC} = MIN,	V _{IH} = 2 V,	IOL = 8 mA					0.35	0.5	\ \ \
11	V _{CC} = MAX,	V ₁ = 7 V				0.1			0.1	mΑ
ΉΗ	V _{CC} = MAX.	V ₁ = 2.7 V				20			20	μА
l L	V _{CC} = MAX,	V ₁ = 0.4 V				- 0.4			- 0.4	mΑ
ГССН	V _{CC} = MAX,	V ₁ = 0			0.4	8.0		0.4	0.8	mΑ
¹ CCL	V _{CC} = MAX,	V ₁ = 4.5 V			1.2	2.2		1.2	2.2	mA

[†] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

switching characteristics, VCC = 5 V, $TA = 25^{\circ}C$ (see note 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONE	TEST CONDITIONS		ТҮР	MAX	UNIT
tрĻН	Any	Y	$R_1 = 2 k\Omega$,	C _I = 15 pF		17	32	ns
tPHL.		•	//[o_ 10 pi		15	28	ns

NOTE 2: Load circuits and voltage waveforms are shown in Section 1.



[‡] All typical values are at V_{CC} = 5 V, T_A = 25°C.

SN54S22, SN74S22 DUAL 4-INPUT POSITIVE NAND GATES WITH OPEN-COLLECTOR OUTPUTS

recommended operating conditions

			SN54S22 SN74S22			UNIT		
		MIN	MOM	MAX	MIN	NOM	MAX	Olait
V _{CC} Sup	oply voltage	4.5	5	5.5	4.75	5	5.25	٧
V _{IH} Hig	nh-level input voltage	2			2			V
VIL Lo	w-level input voltage			0,8			8,0	٧
V _{OH} Hig	h-level output voltage			5.5			5.5	٧
IOL Lo	w-level output current			20			20	mA
T _A Op	erating free-air temperature	- 55		125	0	•	70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

	TEST CONDITIONS†	SN54S22	SN74S22	TINU
PARAMETER	TEST CONDITIONS	MIN TYP [‡] MAX	MIN TYP [‡] MAX	UNIT
Vik	V _{CC} = MIN, I _I = -18 mA	-1.2	-1.2	٧
	V _{CC} = MIN, V _{IL} = 0.8 V, V _{OH} = 5.5 V		0.25	mA.
10н	VCC = MIN, VIL = 0.7 V, VOH = 5.5 V	0.25		IIIA
VOL	V _{CC} = MIN, V _{IH} = 2 V, I _{QL} = 20 mA	0.5	0.5	V
l _l	V _{CC} = MAX, V _I = 5.5 V	1	1	mΑ
IH	VCC = MAX, VI = 2.7 V	50	50	μΑ
l L	$V_{CC} = MAX$, $V_{\parallel} = 0.5 \text{ V}$	-2	-2	mA
Іссн	$V_{CC} = MAX$, $V_{I} = 0$	3 6.6	3 6.6	mΑ
ICCL	$V_{CC} = MAX$, $V_{\parallel} = 4.5 \text{ V}$	10 18	10 18	mA

 $^{^{\}dagger}$ For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions. ‡ All typical values are at V_{CC} = 5 V, T_A = 25 °C.

switching characteristics, VCC = 5 V, TA = 25°C (see note 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CON	MIN	TYP	MAX	UNIT	
t P LH			D 700 0	C 15 - E	2	5	7.5	ns
tPHL	Any	Y	R _L = 280 Ω,	C _L ≈ 15 pF	2	4.5	7	ns
t _{PLH}	Απγ	,	D - 200 O	0 .505		7.5		ns
†PH L			R _L ⇒ 280 Ω,	C _L = 50 pF		7		ns

NOTE 2: Load circuits and voltage waveforms are shown in Section 1.



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